

Contact type : Semi-automatic system

➔ **Cresbox** Small foot print model of semi-automatic 4 point probe sheet resistance/resistivity measurement



Selling Points

User programable measurement pattern & programmable measuring pattern
 Tester self-test function, wide measuring range
 Thickness, edge, temperature correction for silicon wafer
 Film thickness conversion function from sheet resistance

Details

Applications

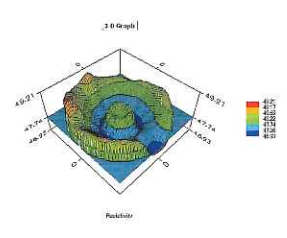
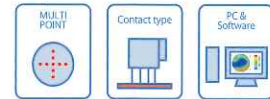
Semiconductor materials, Solar-cell materials (Silicon, Polysilicon, SiC etc)
 New materials, functional materials (Carbon nanotube, DLC, graphene, Ag nanowire etc)
 Conductive thin film (Metal, ITO etc)
 Diffused sample (or layer)
 Silicon-related epitaxial materials, Ion-implantation sample
 Others (*Please contact us for details)

Sample sizes

~ 8 inch, ~156x156mm

Measuring range

[R] 1m~300k Ω·cm
 [RS] 5m~10M Ω/sq



➔ **RT-3000/RG-2000** Wide measurement range model of semi-automatic 4 point probe sheet resistance/resistivity measurement



Selling Points

User programable measurement pattern & programmable measuring pattern
 Tester self-test function, wide measuring range
 Thickness, edge, temperature correction for silicon wafer
 Film thickness conversion function from sheet resistance

Details

Applications

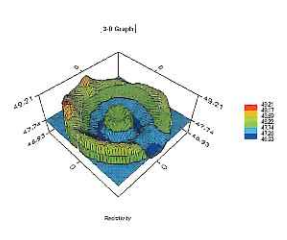
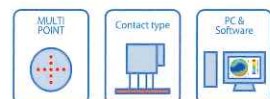
Semiconductor materials, Solar-cell materials (Silicon, Polysilicon, SiC etc)
 New materials, functional materials (Carbon nanotube, DLC, graphene, Ag nanowire etc)
 Conductive thin film (Metal, ITO etc), Diffused sample (or layer)
 Silicon-related thin films (LTPS etc), IGZO
 Silicon-related epitaxial materials, Ion-implantation sample
 Others (*Please contact us for details)

Sample sizes

~ 8 inch, ~156x156mm
 -Option(Large size stage: Model RG-3000); ~12 inch, ~210x210mm

Measuring range

① RT-3000(S) version;
 [R] 100μ~1M Ω·cm [RS] 1m~10M Ω/sq
 ② RT-3000(H) version;
 [RS] 10mΩ/sq~1GΩ/sq



Non-contact type : Semi-automatic system

➔ **NC-80MAP** Non-contact sheet resistance multi-points measurement system with wide range



Selling Points

Possible to measure wide range of sheet resistance by installing Max. 4 probes
 Min. 8 mm position from edge can be measured
 User programable measurement pattern & programmable measuring pattern
 *Option: thickness measurement probe (for silicon wafer)

Details

Applications

Semiconductor materials, Solar-cell materials (Silicon, Polysilicon, SiC etc)
 New materials, functional materials (Carbon nanotube, DLC, graphene, Ag nanowire etc)
 Conductive thin film (Metal, ITO etc), Silicon-related epitaxial materials, Ion-implantation sample
 Chemical compound semiconductor (GaAs Epi, GaN Epi, InP, Ga etc)
 Others (*Please contact us for details)

Sample sizes

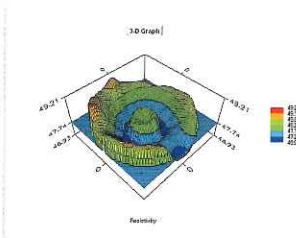
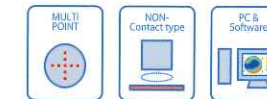
2 ~ 8 inch (Option; 12 inch)

Measuring range

[R] 1m ~ 200 Ω·cm
 [RS] 10m ~ 3,000 Ω/sq

*The range is separated from each Low, Middle, High and S-High probe type.
 *Please refer the measurement range for each probe type as below;

① Low : 0.01~0.5Ω/sq (0.001~0.05Ω·cm) ③ High : 10~1000Ω/sq (0.5~60Ω·cm)
 ② Middle : 0.5~10Ω/sq (0.05~0.5Ω·cm) ④ S-High : 1000~3000Ω/sq (60~200Ω·cm)



➔ **CRN-100** Non-contact Ultra-High range sheet resistance measurement system



Selling Points

Ultra-High range sheet resistance measurement for 10E+9 ~ 10E+15 ohm/sq without contacting
 Mapping program software;
 1. Arranged in a multipoint pattern measurement is programmed
 2. 2-D & 3-D mapping software
 Easy operation by Windows 7 system software
 Measurement data base link with Excel via CSV format file
 Unaffected by contact resistance
 *Corona Discharge Method : Pat. No.5510629
 Joint development with Yamagata Univ.
 (Associate Professor : Dr. Toshiyuki Sugimoto)

Details

Applications

Any sample within the measurement range can be measured.
 Thin film layer (a-Si, IGZO etc), Coating material, Semiconductor material
 Approximate material as Insulator *Please contact us for details.

Sample sizes

Size : Max. 300 x 400 mm (or more) Thickness : Max. 2 mm
 *We can design as your requirement. Please contact us for customize.

Measuring range

10E+9 ~ 10E+15 ohm/sq

